

Search Notes

Application/Control No.

09/539,421

Examiner

Ellen C. Tran

Applicant(s)/Patent under
Reexamination

MITSUI, YASUHIRO

Art Unit

2134

SEARCHED

Class	Subclass	Date	Examiner
713	176	8/19/2005	ECT
380	28	8/19/2005	ECT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	8/19/2005	ECT

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382	100	2/23/2005	ECT
380	100	2/23/2005	ECT
380	54	2/23/2005	ECT
713	176	2/23/2005	ECT
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Class	Sub.	Date	Exmr.
380	3-55	26 Dec 2017	EF
392	100-20	↓	↓
383	17-905		
355	79		
705	51		
713	176		

SEARCH NOTES

(INCLUDING SEARCH STRATEGY)

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INTERFERENCE SEARCHED

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	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	3/13/2006	ECT
PALM, INVENTOR	3/13/2006	ECT
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	8/22/2006	ECT